

First Named		
Inventor	: David J. Larson et al.	
Appln. No.	:	
Filed	: Herewith	Group Art Unit:
Title	: HIGH MAGNETIC ANISOTROPY HARD MAGNETIC BIAS ELEMENT	Examiner:
Docket No.	: I69.12-0609	

INFORMATION DISCLOSURE STATEMENT

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I CERTIFY THAT THIS PAPER IS BEING SENT BY EXPRESS MAIL,
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 ALEXANDRIA, VA 22313-1450, THIS 17 DAY OF

November, 2003.

 PATENT ATTORNEY

Sir:

The enclosed PTO Form-1449 lists patents and publications submitted pursuant to 37 C.F.R. 1.97.
 Copies of the patents or publications are enclosed as necessary.

This application relies, under 35 U.S.C. 120, on the earlier filing date of prior Application No. __ filed on ___. The following references, listed on the enclosed PTO Form 1449 were submitted to and/or cited by the Office in the prior application; therefore, under 37 C.F.R. 1.98(d), copies are not required to be provided herewith:

Submitted herewith is a copy (with English translation as appropriate) of an Official Search Report of the __ Patent Office in counterpart foreign Application No. __ filed __.

The following foreign language documents and English language documents are believed to be equivalent or substantially equivalent:

FOREIGN LANGUAGE

ENGLISH LANGUAGE

TIME OF FILING

The Information Disclosure Statement is being filed:

1. X with the application or within three months of the filing date of a national application (other than a continued prosecution application under 37 C.F.R. 1.53(d)) or date of entry into the national stage of an international application or, to the best of the undersigned's knowledge, before the mailing date of a first Office action on the merits or a first office action after the filing of a request for continued examination under 37 C.F.R. 1.114, whichever event occurs last. In accordance with 37 C.F.R.

1.97(b), no certification or fee is required.

2. after the time period specified in paragraph 1 above, but, to the best of the undersigned's knowledge, before the mailing date of a final action under 37 C.F.R. 1.113 or notice of allowance under 37 C.F.R. 1.311, or an action that otherwise closes prosecution of the application. In accordance with 37 C.F.R. 1.97(c), submitted herewith is:

(check either A or B below)

- A. a statement as specified in 37 C.F.R. 1.97(e), no fee is required.
- B. the fee set forth in 37 C.F.R. 1.17(p) for submission of an Information Disclosure Statement under 37 C.F.R. 1.97(c).

3. after the mailing date of either a final action under 37 C.F.R. 1.113 or a Notice of Allowance under 37 C.F.R. 1.311, whichever occurs first, but on or before payment of the issue fee. Applicant petitions for consideration of this Information Disclosure Statement pursuant to 37 C.F.R. 1.97(d)(2). Applicant submits herewith:

- A. a statement as specified in 37 C.F.R. 1.97(e); and
- B. the fee set forth in 37 C.F.R. 1.17(p).

Respectfully submitted,

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FORM PTO-1449		Atty. Docket No.: I69.12-0609	Application No.:
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT		First Named Inventor: David J. Larson et al.	
		Filing Date: Herewith	Group Art:

U.S. PATENT DOCUMENTS

Examiner Initials	Document No.	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Documents
AA			
AB			
AC			
AD			
AE			
AF			
AG			
AH			
AI			
AJ			
AK			

FOREIGN PATENT DOCUMENTS

		Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Documents	Translation Yes No
	AL				
	AM				
	AN				

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OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

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AP	L.T. Nguyen, A. Lisfi, J.C. Lodder, The effects of metallic underlayers on magnetic properties of obliquely sputtered Co thin films, 2002, Pages 374-377.
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AR	Y. Ueda, W. Takakura, A. Yamada, Electrical resistivity and magnetism of Fe/Si multilayers prepared by oblique incidence evaporation, 2002, Pages 45-47.
AS	A.J. Shapiro, V.S. Gornakov, V.I. Nikitenko, R.D. McMichael, W.F. Egelhoff, Y.W. Tahk, R.D. Shull, Li Gan, Features of domain nucleation and growth in Co/Ru/Co synthetic antiferromagnets deposited on obliquely sputtered Ta underlayers, 2002, Pages 70-72.
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AU	Jongill Hong, Member, IEEE, and Shan X. Wang, Member, IEEE Microstructures of FeTaN Films in the Neck Region of Magnetic Recording Heads, July 2001, Pages 3039-3042.
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AW	R.D. McMichael, C.G. Lee, J.E. Bonevich, P.J. Chen, W. Miller, and W. F. Egelhoff, Jr., Strong anisotropy in thin magnetic films deposited on obliquely sputtered Ta underlayers, November 1, 2000, Pages 5296-5299.
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BB	M. Michijima, H. Hayashi, M. Kyoho, T. Nakabayashi, T. Komoda, T. Kira, T. Kira, Oblique-Incidence Anisotropy in Very Thin Ni-Fe Films, 1999, Pages 3442-3444.
BC	K. Itoh, K. Okamoto, T. Hashimoto, Crystallographic contribution to the formation of the columnar grain structure in cobalt films deposited at oblique incidence, 1998, Pages 176-182.

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OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	BD	M. D. Bijker, E. M. Visser and J. C. Lodder, Oblique metal deposited thin films for magnetic recording, 1999, Pages 553-560.
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	BG	J.M. Alameda, F. Carmona, F.H. Salas, L.M. Alvarez-Prado, R. Morales, G.T. Perez, Effects of the initial stages of film growth on the magnetic anisotropy of obliquely-deposited cobalt thin films, 1995, Pages 249-253.
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	BI	H. Ono, M. Ishida, M. Fujinaga, H. Shishido, and H. Inaba, Texture, microstructure, and magnetic properties of Fe-Co alloy films formed by sputtering at an oblique angle of incidence, 1993, Pages 5124-5128.
	BJ	Y. F. Zheng and J. P. Wang and V. Ng; Control of the tilted orientation of C.CrPt/Ti thin film media by collimated sputtering; Journal of Applied Physics Volume 91, Number 10; May 15, 2002; Pages 8007-8009.

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